

## PCN# 20131218001 Qualification of Alternate Assembly site for select WCSP devices Change Notification / Sample Request

**Date:** 12/30/2013 **To:** Digi-Key PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (<u>PCN ww admin team@list.ti.com</u>).

Sincerely,

PCN Team SC Business Services Phone: +1(214) 480-6037 Fax: +1(214) 480-6659

### 20131218001 Attachment: 1

# **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

# DEVICE

#### **CUSTOMER PART NUMBER**

TCA6418EYFPR TCA8418EYFPR TPS22921YZPR TPS22946YZPR TPS22906YZVR null null null null null

Technical details of this Product Change follow on the next page(s).

PCN Number:	20131218001 PCN Date: 12/30/2013										
Title: Qualification of Alternate Assembly site for select WCSP devices											
Customer Contact:	PCN Manager		Phone:	+1(214)480-6037			I I O D T I		ality rvices		
Proposed 1 <sup>st</sup> Ship Da	te:	03/30/2014	Estim	ated Sample Avail			ability: 12/30/2013		30/2013		
Change Type:											
Assembly Site		Assembly	Process		$\boxtimes$	Asse	embly Mat	teria	ls		
Design		Electrical S	Specificat	ion		Mech	chanical Specification				
Test Site		Packing/Sł						st Process			
Wafer Bump Site		Wafer Bun	Wafer Bump Material 📃 Wa			Wafe	fer Bump Process				
Wafer Fab Site		Wafer Fab Materials 📃 Wa				Wafe	fer Fab Process				
	Part number change										
PCN Details											
Description of Change:											
Texas Instruments is pleased to announce the qualification of JCAP as an alternate assembly site for the devices listed below. There is no material or dimensional differences between devices assembled at the 2 sites.											
Reason for Change:											
Continuity of Supply											

Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative): None

Changes to product identification resulting from this PCN:					
Assembly Site					
STATS ChipPAC (SCS)	Assembly Site Origin (22L)	ASO: STS			
JCAP	Assembly Site Origin (22L)	ASO: JCP			
Sample product shipping label (not actual product label) TEXAS INSTRUMENTS 20: MSL 2 /260C/1 YEAR SEAL DT OFT: ITEM: 39 LBL: 5A (L)T0:1750 (not actual product label) (1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY (1T) 7523483S12 (P) (2P) REV: (V) 0033317 (20L) CS0: SHE (21L) CC0:USA (2L) AS0: MLA (23L) AC0: MYS					
<b>Topside Device marking</b> : Assembly site code for STS = G Assembly site code for JCP = P					

Product Affected				
TCA6418EYFPR	TCA8418EYFPR	TPS22906YZVR	TPS22921YZPR	
TPS22946YZPR				

Qualification Data: (Approved: June 2009)							
This qualification has been developed for the validation of this change. The qualification data will							
validate that the proposed char	nge meets the app	licable released technic	cal specifi	cations.			
Qualification Device: CD3239 (MSL 1-260C)							
Package / Die Attributes							
Assembly Site & Bump Site:	JCAP	Bump Composition	n: SnAgCu				
# Pins-Designator, Family:	25-YFP, DSBGA	Bump Diamete	r: 0.23n	nm			
Passivation/Coating:	MA21009085						
Qualification: 🗌 Plan 🖄 Test Results							
Reliability Test	Conditions			Sample Size / Fail Lot#1 Lot#2 Lot#3			
				1	Lot#3		
**Steady-state Life Test	150C (168, 3	00 Hrs)	116/0	115/0	116/0		
**High Temp. Storage Bake	150C (500, 1	000 Hrs)	77/0	77/0	77/0		
**Biased HAST	130C/85%RH	130C/85%RH (96 Hrs)		77/0	77/0		
**Unbiased HAST	130C/85%RH	130C/85%RH/33.3 psia (96 Hrs)		77/0	77/0		
**T/C -55C/125C	121C (96 Hrs	121C (96 Hrs)		77/0	77/0		
**Temp Cycle	-55C/+125C	-55C/+125C (500, 1000 Cyc)		77/0	77/0		
Visual Mechanical	Per Manufact	Per Manufacturing Specifications		Pass	Pass		
Physical Dimensions	(per mechani	(per mechanical drawing)			Pass		
**Preconditioning: MSL1@260C							

Reference Qualification Data: (Approved: June 2010)							
This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.							
Qualification Device: TPS22934YZVR (MSL 1-260C)							
Package Construction Details							
Assembly Site & Bump Site:	JCAP	Bump Composition:	SnAgCu				
# Pins-Designator, Family:	4-YZV, DSBGA	Bump Diameter:	0.225mm				
Passivation/Coating:	MA21009085						
Qualification: 🗌 Plan 🛛 Test Results							
Reliability Test	Conditions		Sample Size / Fail				
Visual Mechanical	Per Manufactu	ring Specifications	Pass				
Physical Dimensions	(per mechanic	cal drawing)	Pass				
Bump-shear	(per mfg. Site	specification)	Pass				
Notes: **Tests require preconditioning sequence: MSL1-260C							

Reference Qualification Data: (Approved: April 2008)								
This qualification has been developed for the validation of this change. The qualification data will								
validate that the proposed change meets the applicable released technical specifications.								
Qualification Device: TS3DS26227YZT (MSL 1-260C)								
Package / Die Attributes								
Assembly Site & Bump Site:	JCA	Р	Bump Composition	า: S	n: SnAgCu			
# Pins-Designator, Family:	12-`	YZT, DSBGA	Bump Diamete	r: 0	r: 0.225mm			
Passivation/Coating:	21009085							
Qualification: 🗌 Plan 🛛 Test Results								
Reliability Test	Conditions		Sample Size / Fail					
Reliability Test			Lot#1 Lot#2 Lot#3					
**Steady-state Life Test	150C (168, 30	00 Hrs)	116	5/0	116/0	116/0		
**High Temp. Storage Bake	170C (168, 42	20hrs)	77	/0	77/0	77/0		
**Biased HAST	130C/85%RH	(96 Hrs)	77	/0	77/0	77/0		
**Unbiased HAST	130C/85%RH/33.3 psia (96 Hrs)		77	/0	77/0	77/0		
**T/C -55C/125C	-55C/+125C (500, 1000 Cyc)		77	/0	77/0	77/0		
Visual Mechanical		Per Manufacturing Specifications		Pa	SS	Pass	Pass	
Solderability		Steam age, 8 hours		Pa	SS	Pass	Pass	
Physical Dimensions		(per mechanical drawing)		Pa	SS	Pass	Pass	
Bump-shear		(per mfg. Site specification)		Pa	SS	Pass	Pass	
**Preconditioning: MSL1@260C								

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com